

Application/Control No.	Applicant(s)/Patent u Reexamination	nder
10/645,855	WEWALAARACHC	HI ET AL.
Examiner	Art Unit	
Sved Zaidi	2616	

SEARCHED				
Class	Subclass	Date	Examiner	
370	389	1/29/2008	sz	
Updated	search	1/29/2008	SZ	
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INTERFERENCE SEARCHED				
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SEARCH NOT (INCLUDING SEARCH)
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EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	1/29/2008	SZ
Inventors : WEWALAARACHCHI ET AL.	1/29/2008	SZ
(IEEE Xplore Database(http://ieeexplore.ieee.org/Xp lore/DynWel.jsp)	1/29/2008	SZ
(370/389 370/390 370/351 370/473 370/474).CCLS.	1/29/2008	SZ
Consulted with SPE Ricky NGO370	1/29/2008	SZ
UP DATED SEARCH	1/29/2008	SZ